## Applicant(s)/Patent Under Application/Control No. Reexamination 10/539,038 SATOH ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Rip A. Lee 1713 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 07-2003 Takaoki et al. 502/155 US-6,586,356 B2 Α \* US-6,528,596 B2 03-2003 Takaoki et al. 526/113 В 07-2005 526/89 Takaoki et al. С US-6,914,108 B2 \* US-7,022,782 B2 04-2006 Ogane, Takuya 526/160 D US-6,284,699 B1 09-2001 Ohgane et al. 502/103 Ε US-F US-G US-Н USı US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

\*A copy of this reference is not being furnished with the Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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